



# Power MOSFETS


## DATASHEET

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**LM30025NAP3A**

N-Channel  
Enhancement Mode MOSFET

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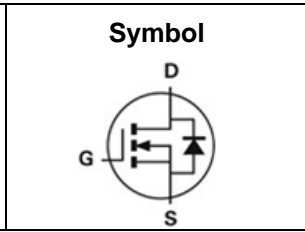
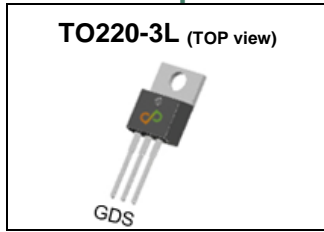


Quality Management Systems

ISO 9001:2015 Certificate

## N-Channel Enhancement Mode MOSFET

### Pin Description



### Product Summary

Symbol	N-Channel	Unit
$V_{DSS}$	30	V
$R_{DS(ON)-Max}$	3	m $\Omega$
ID	133	A

### Feature

- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS Tested

### Applications

- SMPS Synchronous Rectification
- DC-DC Conversion

### Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM30025NAP3A	TO220-3L	Tube	50 / Tube	30025 □□□□□□

### Absolute Maximum Ratings (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit	
$V_{DSS}$	Drain-Source Voltage	30	V	
$V_{GSS}$	Gate-Source Voltage	±20		
$T_J$	Maximum Junction Temperature	150	°C	
$T_{STG}$	Storage Temperature Range	-55 to 150	°C	
$I_{DM}^{①}$	Pulse Drain Current Tested	T <sub>c</sub> =25°C	184	A
$I_D$	Continuous Drain Current	T <sub>c</sub> =25°C	133	A
		T <sub>c</sub> =100°C	84	
$P_D$	Maximum Power Dissipation	T <sub>c</sub> =25°C	83	W
		T <sub>c</sub> =100°C	33	
$I_{AS}^{②}$	Avalanche Current, Single pulse	L=0.1mH	43	A
$E_{AS}^{②}$	Avalanche Energy, Single pulse	L=0.1mH	92	mJ

### Thermal Characteristics

Symbol	Parameter	Rating	Unit	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	1.5	°C/W
$R_{\theta JA}^{③}$	Thermal Resistance-Junction to Ambient	Steady State	62.5	°C/W

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in<sup>2</sup> FR-4 board with 1oz.

## N-Channel Electrical Characteristics (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Electrical Characteristics</b>						
<b>BV<sub>DSS</sub></b>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250uA	30	-	-	V
<b>I<sub>DSS</sub></b>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V	-	-	1	uA
<b>V<sub>GS(th)</sub></b>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250uA	1	1.5	2	V
<b>I<sub>GSS</sub></b>	Gate Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
<b>R<sub>DS(ON)</sub></b> <sup>④</sup>	Drain-Source On-state Resistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =20A	-	2.6	3	mΩ
		V <sub>GS</sub> =4.5V, I <sub>DS</sub> =15A	-	3.4	4.4	
<b>g<sub>fs</sub></b>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>DS</sub> =10A	-	38	-	S
<b>Dynamic Characteristics</b> <sup>®</sup>						
<b>R<sub>G</sub></b>	Gate Resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, Freq.=1MHz	-	2.6	-	Ω
<b>C<sub>iss</sub></b>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, Freq.=1MHz	-	4200	-	pF
<b>C<sub>oss</sub></b>	Output Capacitance					
<b>C<sub>rss</sub></b>	Reverse Transfer Capacitance					
<b>t<sub>d(ON)</sub></b>	Turn-on Delay Time	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =1A, R <sub>GEN</sub> =6Ω	-	33	-	nS
<b>t<sub>r</sub></b>	Turn-on Rise Time					
<b>t<sub>d(OFF)</sub></b>	Turn-off Delay Time					
<b>t<sub>f</sub></b>	Turn-off Fall Time					
<b>Q<sub>g</sub></b>	Total Gate Charge	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =25V, I <sub>D</sub> =14A	-	46	-	nC
<b>Q<sub>g</sub></b>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =25V, I <sub>D</sub> =14A	-	88.1	-	
<b>Q<sub>gs</sub></b>	Gate-Source Charge		-	7.3	-	
<b>Q<sub>gd</sub></b>	Gate-Drain Charge		-	24	-	
<b>Source-Drain Characteristics</b>						
<b>V<sub>SD</sub></b> <sup>④</sup>	Diode Forward Voltage	I <sub>SD</sub> =10A, V <sub>GS</sub> =0V	-	0.8	1.1	V
<b>t<sub>rr</sub></b>	Reverse Recovery Time	I <sub>F</sub> =15A, V <sub>R</sub> =0V	-	19.6	-	nS
<b>Q<sub>rr</sub></b>	Reverse Recovery Charge	dI <sub>F</sub> /dt=100A/μs	-	8.7	-	nC

Note ④ : Pulse test (pulse width≤300us, duty cycle≤2%).

Note ⑤ : Guaranteed by design, not subject to production testing.

## N-Channel Typical Characteristics

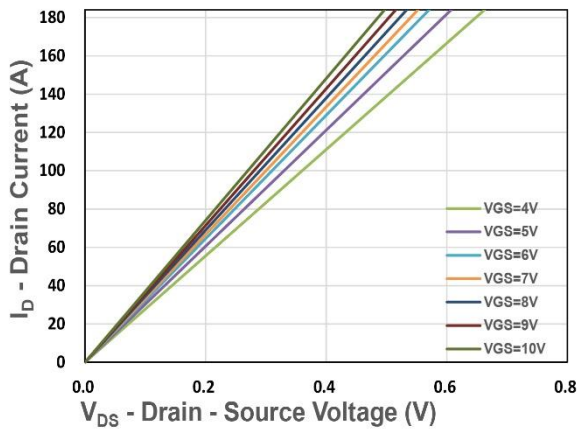


Figure 1. Output Characteristics

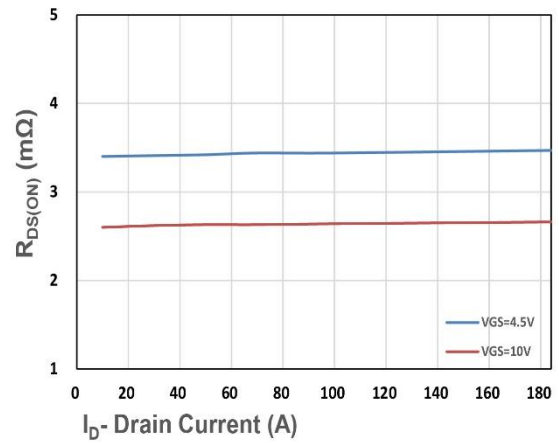


Figure 2. On-Resistance vs.  $I_D$

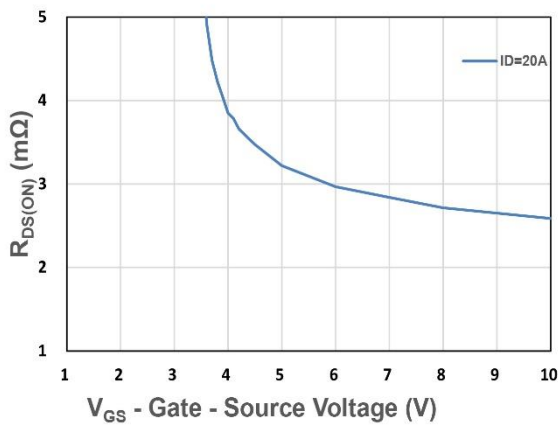


Figure 3. On-Resistance vs.  $V_{GS}$

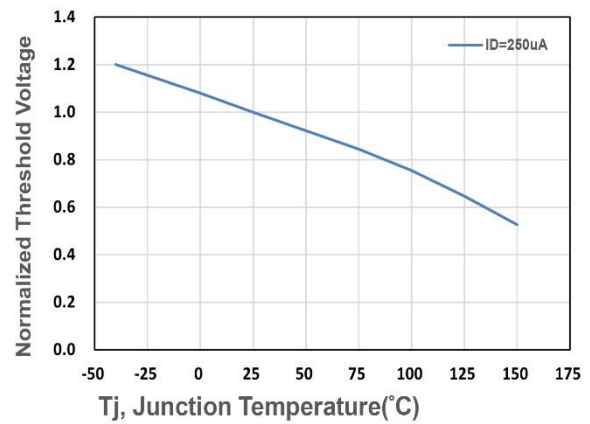


Figure 4. Gate Threshold Voltage

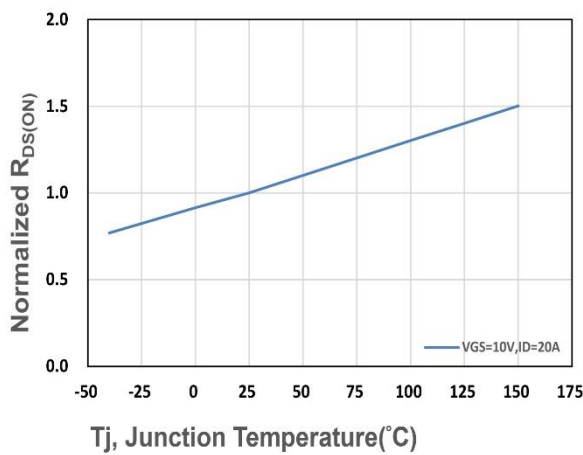


Figure 5. Drain-Source On Resistance

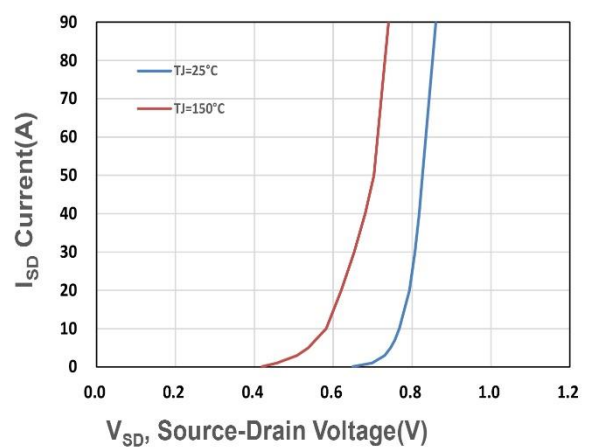


Figure 6. Source-Drain Diode Forward

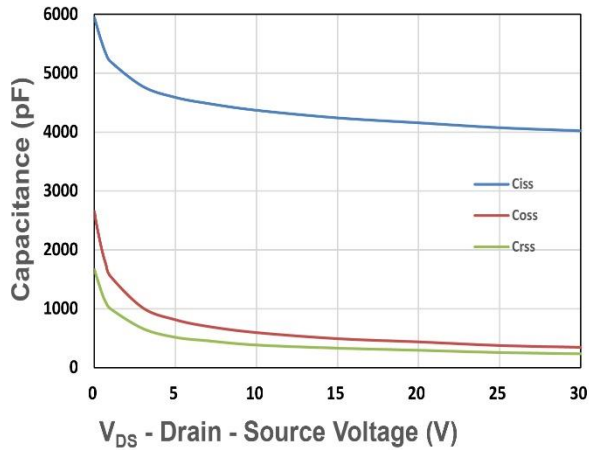


Figure 7. Capacitance

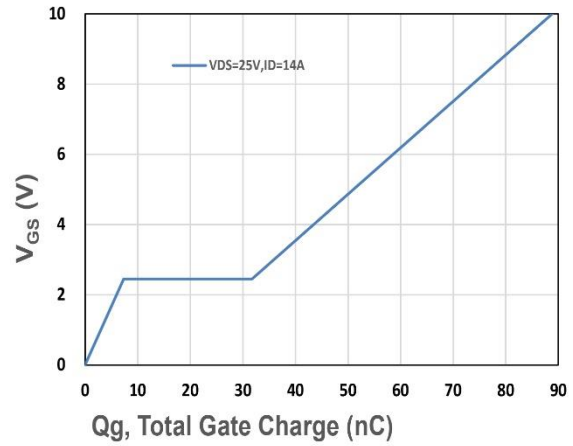


Figure 8. Gate Charge Characteristics

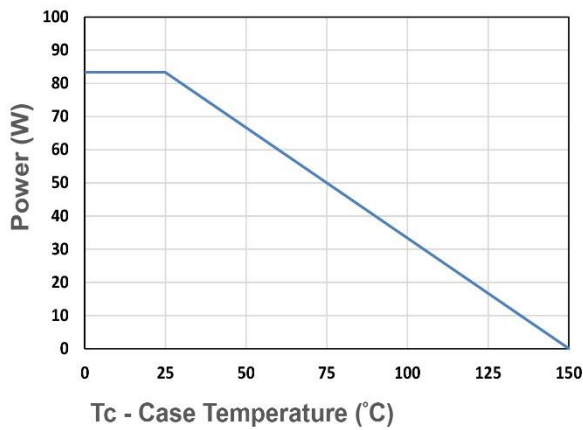


Figure 9. Power Dissipation

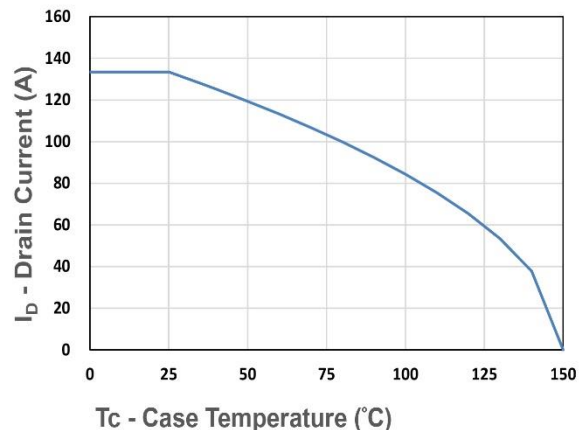


Figure 10. Drain Current

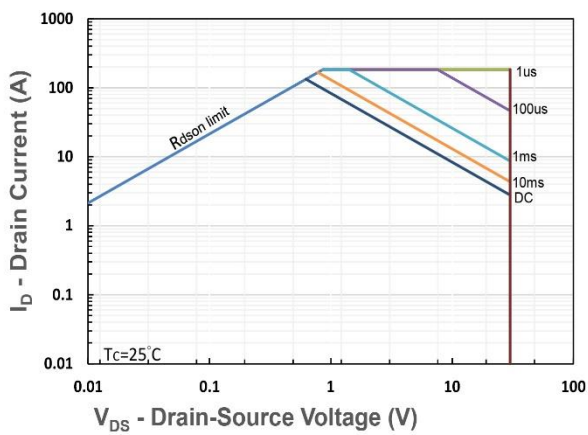


Figure 11. Safe Operating Area

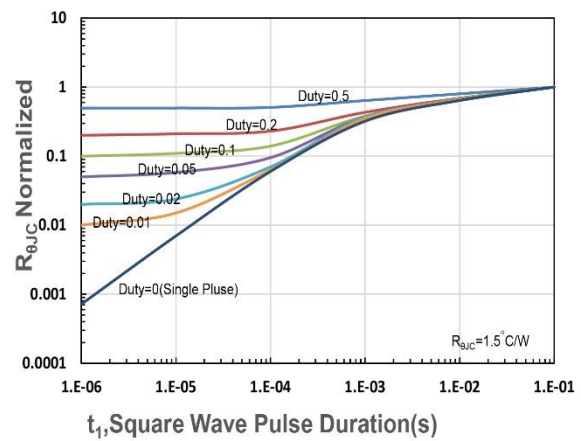


Figure 12.  $R_{\theta JC}$  Transient Thermal Impedance